

Search Notes



Application/Control No.

10/500,736

Examiner

Sang Y. Paik

Applicant(s)/Patent under Reexamination

KACHI ET AL.

Art Unit

3742

SEARCHED

Class	Subclass	Date	Examiner
219	443.1 444.1 390		
392	448		
118	724 725		
8/24/05 JP			

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
GAST TEST REMOVED	8/24/05	JP